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(71) Applicant (for all designated States except US): **XPAR VISION B.V.** [NL/NL]; Radesingel 50, NL-9711 EK Groningen (NL).

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(72) Inventor; and

(75) Inventor/Applicant (for US only): **DALSTRA, Joop** [NL/NL]; Boskamp 18, NL-9753 KH Haren (NL).

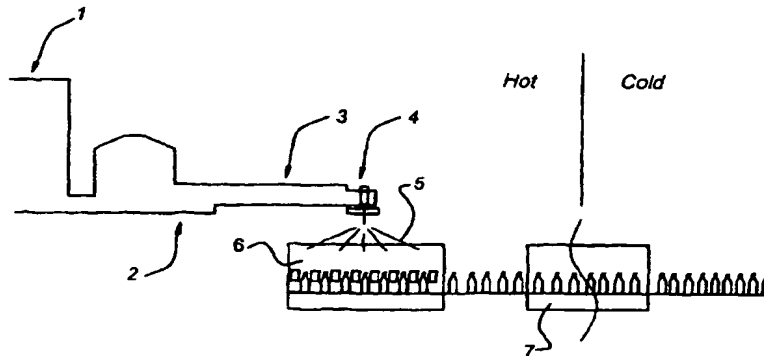
(74) Agent: **VAN WESTENBRUGGE, Andries at al**; Nederlandsch Octrooibureau, Scheveningseweg 82, P.O. Box 29720, NL-2502 LS The Hague (NL).

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(54) Title: ANALYTICAL SYSTEM AND METHOD FOR MEASURING AND CONTROLLING A PRODUCTION PROCESS



(57) **Abstract:** An analytical system for analysing and controlling a shaping process for glass products is described. The analytical system comprises an infrared-sensitive measurement system and a processor communicating therewith, the infrared-sensitive measurement system being equipped to measure infrared radiation originating from hot glass products immediately after the shaping process for the glass products and the processor being equipped to determine a heat distribution in the glass products on the basis of information determined by the measurement system. Because the infrared-sensitive measurement system is sensitive only to radiation in the so-called Near Infra Red (NIR) region, radiation originating from the interior of the glass wall can be measured. This makes novel analytical methods possible with which, inter alia, a distinction can be made between a change in glass wall thickness and a change in temperature.

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